Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/807,425 Examiner	SASAKI ET AL.
Paul D. Kim	3729

SEARCHED					
Class	Subclass	Date	Examiner		
29	603.07 603.12 603.15 603.16 603.18	1/23/2006	PK		
360	235.1- 235.3				
	235.7 235. 8				
	236.1 236.3				
	246.2				
451	4,51	/			
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
1	ext Search achment	6/7/2006	PK	

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
Reviewed Parent Application 10/041,566 (US PAT. 6,731,464,)	1/23/2006	PK
Text Search EAST/NPL (IEEE)	1/23/2006	PK
Updated Text Search East/PGPub	6/7/2006	PK